Verification of Compliance

Product Name

: Fanless Touch Panel

Model Number

: xxxxxAHP-1081xTy -xxxxxxxx

(Where y is T or blank; x is 0-9, A-Z, -or blank) for

marketing purpose

Applicant

: AAEON Technology Inc.

Address

: 5F,No.135,Lane 235,Pao Chiao Rd. Hsin-Tien City,Taipei,

Taiwan, R.O.C.

Report Number

: F-U070-1009-255

Issue Date

: October 12, 2010

Applicable Standards: FCC Part 15, Subpart B Class A ITE

ANSI C63.4:2003

Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE

One sample of the designated product has been tested in our laboratory and found to be in compliance with the FCC rules cited above.





NVLAP LAB CODE 200575-0

TAF 0905 FCC CAB Code TW1053 IC Code 4699A VCCI Accep. No. R-1527, C-1609, T-131, T-1441, G-10



Central Research Technology Co.

EMC Test Laboratory 11, Lane41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.

Tel: 886-2-25984568 Fax: 886-2-25984546

(Tsun-Yu Shih/ General Manager)

Date: October 12, 2010

FCC Test Report

for

Fanless Touch Panel

Model Number : xxxxxAHP-1081xTy -xxxxxxxx

(Where y is T or blank; x is 0-9, A-Z, -or

blank) for marketing purpose

Report Number : F-U070-1009-255

Date of Receipt: September 21, 2010

Date of Report : October 12, 2010

Prepared for

AAEON Technology Inc.

5F,No.135,Lane 235,Pao Chiao Rd. Hsin-Tien City,Taipei,Taiwan,R.O.C.

Prepared by



Central Research Technology Co. EMC Test Laboratory

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.



NVLAP LAB CODE 200575-0

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TEL: 886-2-25984542

Verification of Compliance

: Fanless Touch Panel **Equipment Under Test**

Model No. : xxxxxAHP-1081xTy -xxxxxxxx

(Where y is T or blank; x is 0-9, A-Z, -or blank) for

marketing purpose

Applicant : AAEON Technology Inc.

: 5F,No.135,Lane 235,Pao Chiao Rd. Hsin-Tien City,Taipei, **Address**

Taiwan, R.O.C.

Applicable Standards : FCC Part 15, Subpart B Class A ITE

ANSI C63.4:2003

Industry Canada ICES-003 Issue 4 **CSA-IEC CISPR22: 02 Class A ITE**

Date of Testing : October 2~6, 2010

Deviation : N/A

Condition of Test Sample: Engineering Sample

We, Central Research Technology Co., hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

(Iris Chen/System Executive) PREPARED BY

APPROVED BY

(Tsun-Yu Shih/General Manager)

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1. General Description

1.1 General Description of EUT

Equipment Under Test : Fanless Touch Panel

Model No. : xxxxxAHP-1081xTy –xxxxxxxx

(Where y is T or blank; x is 0-9, A-Z, -or blank)

for marketing purpose

Power in : Supplied by the power adapter.

Power Adapter Specification : Trade Name : FSP

Model No. : FSP040-DGAA1

Input Voltage : 100-240Vac, 50-60Hz, 1.3A

Output Voltage : 12Vdc, 3.33A (40W Max)

DC Power Cable: 1.2m with one core

Highest Operating Frequency : 1.6GHz

Function Description

The EUT is an engineering sample of the Fanless Touch Panel. Please refer to the user's manual for the details.

The I/O ports of EUT are listed below:

No.	I/O Port Type	Quantity
1	D-Sub port	1
2	USB port	2
3	RS232 port	2
4	LAN port	2

The Specifications of EUT supplied by the manufacturer are shown as below:

Devices	Specifications
CPU Board	GENE-9315-xxxxxx (Where x is 0-9 , A-Z , -or blank) for marketing purpose
CPU	INTEL ATOM N270 1.6GHz
Memory	DSL , 1GB , DDR2-667 1GB , M/N : ELPIDA E5108AG- 6E-E
Hard Disk	Toshiba , HDD2H85 160GB
AC Adapter	FSP , Model : FSP040-DGAA1 , O/P : 12V/3.33A , 40Watt
EUT POWER RATING	12VDC
OSC	32.768KHZ; 25MHZ; 14.31818MHZ

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1.2 Test Mode

Normal operation as the specification of the manufacturer.

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1.3 Applied standards

According to the specifications of the manufacturer and the requirements set in 47CFR Part 15, Subpart B, the applied standards to evaluate the compliance of the EUT are as following, and the measurement procedures specified in ANSI C63.4: 2003 are performed.

According to 47CFR Part 15 Section 15.33(b), the test frequency range of radiated emission measurements are listed below and the EUT herein shall be tested as:

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 1.705	30
	1.705 - 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 th harmonic of the highest
	Above 1000	frequency or 40GHz,
		whichever is lower

All the test items are as following:

Applied Standards	Test Items	Results
FCC Part 15, Subpart B	☑ Conducted Emission Measurement	<u>PASS</u>
Class A ITE	☑ Radiated Emission Measurement	<u>PASS</u>

1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard through the following steps:

- a. Connect the EUT and all the support units to the appropriate power source.
- b. Turn on the EUT and all the accessories and support units.
- c. Install an EMC test software into EUT and execute it under the Windows environment.
- d. The EUT sends "H" patterns to the monitor which fills the whole screen of it.
- e. The EUT sends message to the modems.
- f. Another PC sends/ receives messages to/ from the EUT through a Hub by executing the command of "PING".
- g. Repeat and keep setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program	
Monitor	BurnIn Test.exe	V4.0	
Modem	Barriiri Toolioxo		

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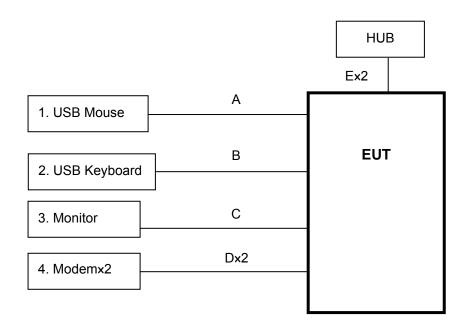
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The Support Units 1.5

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.	Note
1	USB Mouse	MOC5U0 / G1E03M10	DoC	DELL	N/A	✓	
2	USB Keyboard	SK-8115/ CN-0J4635-71616- 55G-0AHO	DoC	DELL	N/A	✓	
3		U2410 / CN-0J257M-72872- 070-02JL	DoC	DELL	1.8m	√	Used for RE test
	Monitor	2408WFP/ CN-0NN792-74261- 849-154S	DoC	DELL	1.8m	√	Used for CE test
4	Modom	DM-1414/ 0509019804	IFAXDM1414	ACEEX	1.8m	✓	
	Modem -	DM-1414/ 0509019803	IFAXDM1414	ACEEX	1.8m	✓	_

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1.6 Layout of the Setup



Connecting Cables:

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	USB Mouse Cable	1.8m	✓			✓	
В	USB Keyboard Cable	1.8m	✓			✓	
С	D-Sub Cable	1.8m	✓	✓		✓	2 cores
D	Modem Cable	1.8m	✓	✓		✓	2 cores
Е	LAN Cable	1.8m				✓	

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1.7 Test Capability

Test Facility

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3 and ANSI C63.4: 2003.

Test Room	Type of Test Room	Descriptions
TR1	10m semi-anechoic chamber (23m \times 14m \times 9m)	Complying with the NSA requirements in documents CISPR 22 and
TR11	3m semi-anechoic chamber	ANSI C63.4: 2003. for the radiated
IKII	$(9m \times 6m \times 6m)$	emission measurement.
TR5	Shielding Room	For the conducted emission
IKS	$(8m \times 5m \times 4m)$	measurement.

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Test Laboratory Competence Information

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark
	USA	NVLAP	200575-0	ISO/IEC 17025
	R.O.C. (Taiwan)	TAF	0905	ISO/IEC 17025
Accreditation Certificate	R.O.C. (Taiwan)	BSMI	SL2-IN-E-0033, SL2-IS-E-0033, SL2-R1/R2-E-0033, SL2-A1-E-0033 SL2-L1-E-0033	ISO/IEC 17025
	USA	FCC	474046,TW1053	Test facility list & NSA Data
Site Filing Document	Canada	IC	4699A-1,-3	Test facility list & NSA Data
	Japan	VCCI	R-1527,C-1609,T-131,T-1441, G-10	Test facility list & NSA Data
Authorization	Germany	TUV	10021687-2010	ISO/IEC 17025
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

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2. Conducted Emission Measurement

Test Result : PASS

2.1 Limits for Emission Measurement

☑ Limits for conducted disturbances at the power mains

Frequency	Class A E	quipment	Class B Equipment		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
(1711 12)	(dBµV)	(dBµV)	(dBµV)	(dBµV)	
0.15 to 0.5	79	66	66 – 56	56 – 46	
0.5 to 5	73	60	56	46	
5 to 30	73	60	60	50	

Note 1- The lower limit shall apply at the transition frequency.

Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

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Test Instruments 2.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manufacture	Serial No.	Calibration Date	Due Date	
Test Receiver	R&S	ESCS 30/	lan 40 0040	lon 12 2011	
lest Receiver	Κασ	836858/021	Jan. 12, 2010	Jan. 12, 2011	
LISN	R&S	ESH2-Z5/	May 26, 2010	May 26, 2011	
LISIN	Κασ	836613/001	May 26, 2010	May 26, 2011	
2 nd LISN	R&S	ENV4200/	lon 12 2010	lon 12 2011	
2 LISIN	Κασ	833209/010	Jan. 12, 2010	Jan. 12, 2011	
50Ω terminator	N/A	N/A/	Aug. 26, 2010	Aug. 26, 2011	
5012 terminator	IN/A	001			
RF Switch	N/A	RSU28/	Aug. 23, 2010	Feb. 23, 2011	
KF SWILCH	IN/A	338965/002			
RF Cable	N/A	N/A/	Aug 22 2010	Fab 22 2011	
KF Cable	IN/A	C0052 ~ 56	Aug. 23, 2010	Feb. 23, 2011	
Test Software	Audix	e3/	NCR	NOD	
1681 Sollware	Audix	Ver. 5.2004-2-19k	NCR	NCR	
TR5	ETS	TR5/	NCR	NCD	
shielded room	LINDGREN	15353-F	NOR	NCR	

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value
LISN	ESH2-Z5	3.1dB
	ENV 4200	2.8dB

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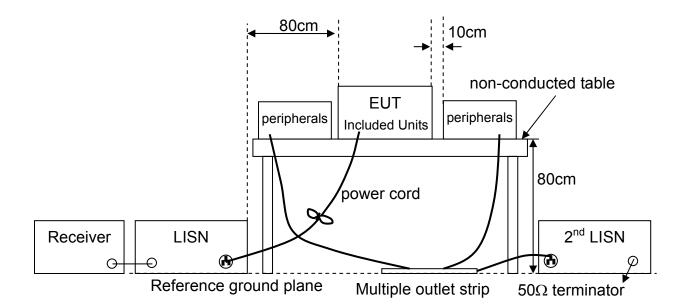
2.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane.
- c. Connect the EUT's power source to the appropriate power mains through the LISN.
- d. All the other peripherals are connected to the 2nd LISN, if any.
- e. The LISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- Record the level for each frequency and compare with the required limit.

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2.4 Test Configurations



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Photographs of the Test Configurations 2.5





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2.6 Test Results

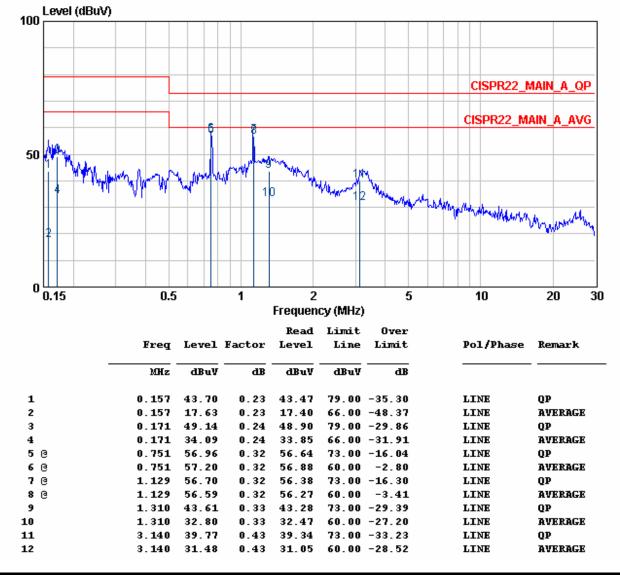
Test Mode : Normal

Test Voltage: 120V/60Hz to the power adapter

Tester : Kent Temperature : 27°C

Humidity: 53%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Line



Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

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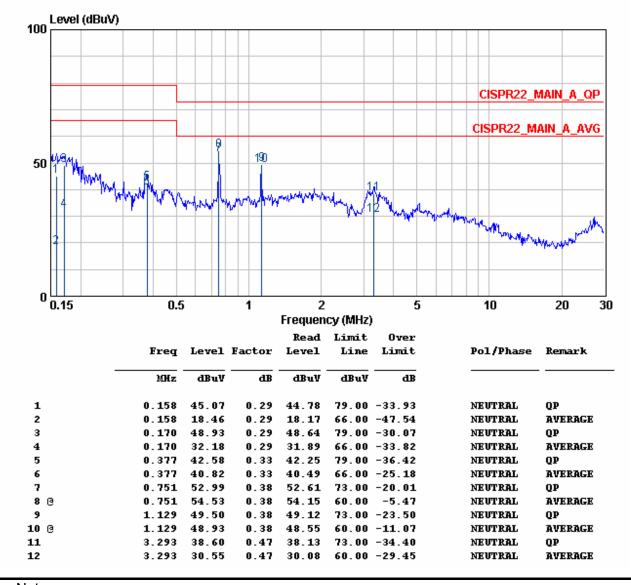
Test Mode : Normal

Test Voltage: 120V/60Hz to the power adapter

Tester: Kent **Temperature**: 27°C

Humidity: 53%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Neutral



Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

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3. Radiated Emission Measurement

Test Result : PASS

3.1 Limits for Emission Measurement

☑ Limits for radiated disturbances below 1000MHz

Frequency	Class A Equipment (10m distance)	Class B Equipment (3m distance)
(MHz)	Quasi-peak	Quasi-peak
	(dBµV/m)	(dBµV/m)
30 to 88	39.1	40
88 to 216	43.5	43.5
216 to 960	46.4	46
960 to 1000	49.5	54

Note 1- The lower limit shall apply at the transition frequency.

Note 2- Additional provisions may be required for cases where interference occurs.

Note 3- According to 15.109(g), as an alternative to the radiated emission limits shown above, digital devices may be shown to comply with the standards (CISPR), Pub. 22 shown as below.

- P		
30 to 230	40	30
230 to 1000	47	37

☐ Limits for radiated disturbances in the frequency range 1000MHz ~ 2000MHz at a measuring distance of 10m

Frequency (GHz)	Class A Ed	quipment	Class B Equipment		
	Peak	Average	Peak	Average	
	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)	
1 to 2	69.5	49.5	63.5	43.5	

☑ Limits for radiated disturbances above 1000MHz at a measuring distance of 3m

Frequency	Class A Ed	quipment	Class B Equipment	
(GHz)	Peak	Average	Peak	Average
	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 40	80	60	74	54

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3.2 Test Instruments

☑ For Measurement at the distance of 10m

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
EMI Test Receiver	R&S	ESCS 30/ 836858/020	Aug. 20, 2010	Aug. 20, 2011
Broadband Antenna	R&S	HL-562/ 360543/007	March 19, 2010	March 19, 2011
Broadband Antenna	R&S	HL-562/ 830547/010	April 29, 2010	April 29, 2011
Pre-Amplifier	Mini Circuit	ZKL-2/ 001	July 20, 2010	Jan. 20, 2011
Pre-Amplifier	Mini Circuit	ZKL-2/ 002	July 20, 2010	Jan. 20, 2011
Spectrum	R&S	FSP7/ 100108	June 4, 2010	June 4, 2011
Spectrum	R&S	FSP7/ 100384	Dec. 18, 2009	Dec. 18, 2010
RF Cable	JYEBAO	0214/ C0049	July 20, 2010	Jan. 20, 2011
RF Cable	JYEBAO	0214/ C0050	July 20, 2010	Jan. 20, 2011
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	April 24, 2010	April 24, 2011

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

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☑ For Measurement at the distance of 3m

Test Site and Equipment	Manufacturer	Model No./ Serial No.		Last Calibration Date	Calibration Due Date
EMI Test Receiver	R&S	ESCI/ 100019		May 19, 2010	May 19, 2011
Bi-Log Antenna	EMCO		3142C/ 52088	May 18, 2010	May 18, 2011
Horn Antenna	EMCO		3117/ 57416	March 5, 2010	March 5, 2011
Bore-sight Antenna Mast	Sunol		TLT2/ 051110-5	NCR	NCR
	KMIC		KMA010180A01/ 99056	Sept. 30, 2010	Sept. 30, 2011
Pre-Amplifier	Mini Circuit		ZKL-2/ 004	Aug. 6, 2010	Feb. 6, 2011
r re-Amplinei	MITEQ	V	JJS4-00101800- 28-5A/742229	Dec.15, 2009	Dec.15, 2010
	MITEQ		JJS4-00101800- 28-5A/742309	Dec. 22, 2009	Dec. 22, 2010
Spectrum Analyzer	Agilent		E4407B/ MY45106795	May 4, 2010	May 4, 2011
RF Cable	N/A	N/A/ C0080		Aug. 6, 2010	Feb. 6, 2011
RF Cable	N/A	N/A/ C0081		April 21, 2010	Oct. 21, 2010
Test Software	Audix	e3/ Ver. 4.3.714.e		NCR	NCR
TR11 Semi - anechoic Chamber	ETS. LINDGREN	TR11/ 906-A		April 19, 2010	April 19, 2011

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

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Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Test Site	Polarization	Frequency Range		
(Measuring distance)	1 Glarization	30MHz ~200MHz	200MHz ~1000MHz	
TR1(10m)	Horizontal	3.5dB	3.9dB	
Trent Tolling	Vertical	3.5dB	3.9dB	
TR11(3m)	Horizontal	3.5dB	3.9dB	
Tixti(oiii)	Vertical	3.8dB	3.9dB	

Test Site	Polarization	Frequency Range		
(Measuring distance)	1 Glarization	1GHz ~18GHz	18GHz~26GHz	
TR11(3m)	Horizontal	3.5dB	4.4dB	
Trent(om)	Vertical	3.6dB	4.5dB	

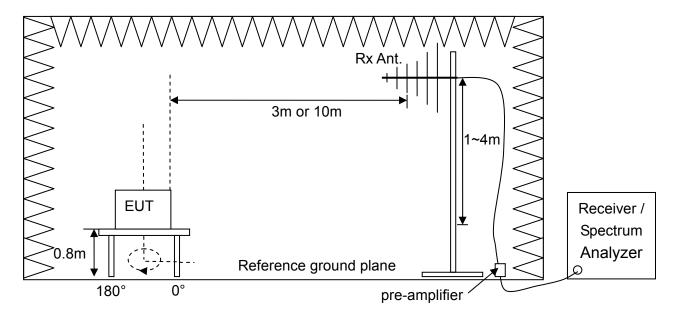
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3.3 Test Procedures

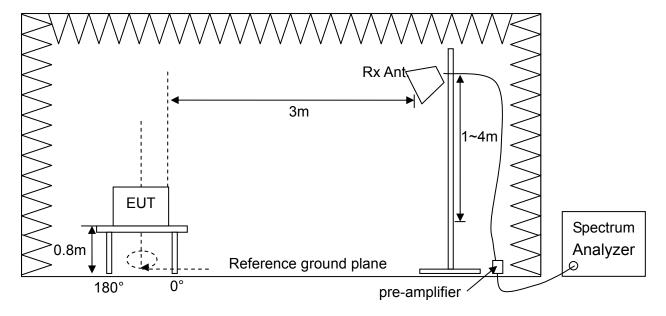
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane in the semi-anechoic chamber. If the EUT is floor-standing equipment, it was placed on a nonconducted support with a height of 12 millimeters above the reference ground plane in the semi-anechoic chamber.
- c. For the measurement of frequency below 1000MHz, the EUT was set 10m away from the interference receiving antenna for the limit of Class A equipment or CISPR 22. For Class B equipment and the measurement of frequency above 1000MHz, the EUT was set 3m away from the interference receiving antenna.
- d. Rapidly sweep the signal in the test frequency range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. For measurement of frequency above 1000MHz, the beamwidth of receiving horn antenna should keep covering EUT when the receiving horn antenna height varied.
- g. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- h. Finely tune the antenna and turntable around the recorded position of each frequency found from step f.
- For measurement of frequency below 1000MHz, set the receiver detector to be Quasi-Peak per CISPR 16-1 to find out the maximum level occurred.
- For measurement of frequency above 1000MHz, set the spectrum detector to be Peak or Average to find out the maximum level occurred, if any.
- k. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- I. Change the receiving antenna to another polarization to measure radiated emission by following step d. to k. again.
- m. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

3.4 Test Configurations

Radiated Emission Measurement below 2000MHz



Radiated Emission Measurement above 1000MHz (if any)



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Photographs of the Test Configurations 3.5





3.6 Test Results

Radiated Emission Measurement below 1000MHz

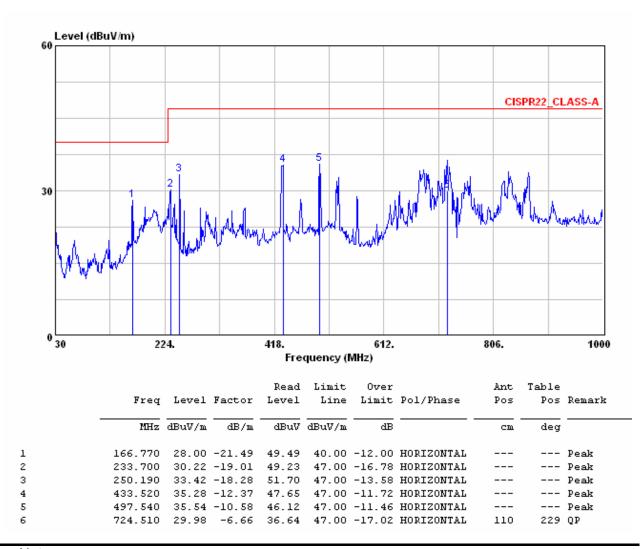
Test Mode : Normal

Test Voltage: 120V/60Hz to the power adapter

Tester : Meng Lin Temperature : 27°C

Humidity: 70%RH Frequency Range: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Horizontal



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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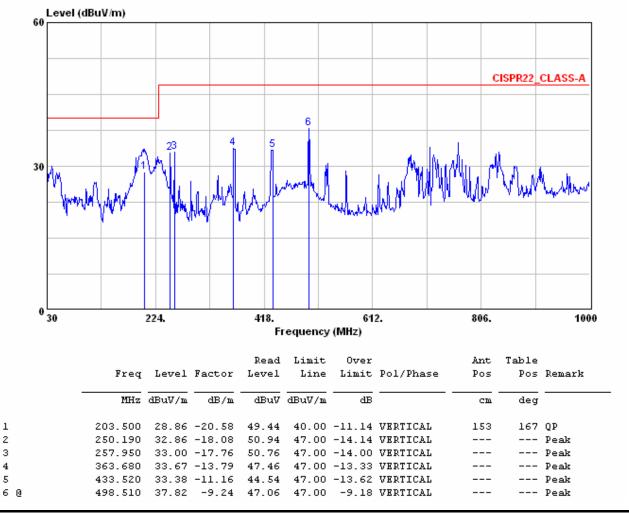
Test Mode : Normal

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng Lin **Temperature**: 27°C

Humidity: 70%RH Frequency Range: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Vertical



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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Radiated Emission Measurement above 1000MHz

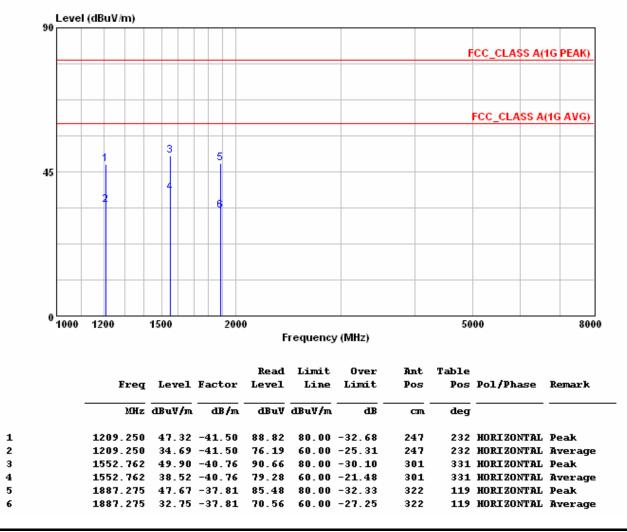
Test Mode : Normal

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng Lin **Temperature**: 23°C

Humidity: 65%RH Frequency Range: 1GHz ~8GHz

IF Bandwidth: 1MHz Polarization: Horizontal



Note:

- Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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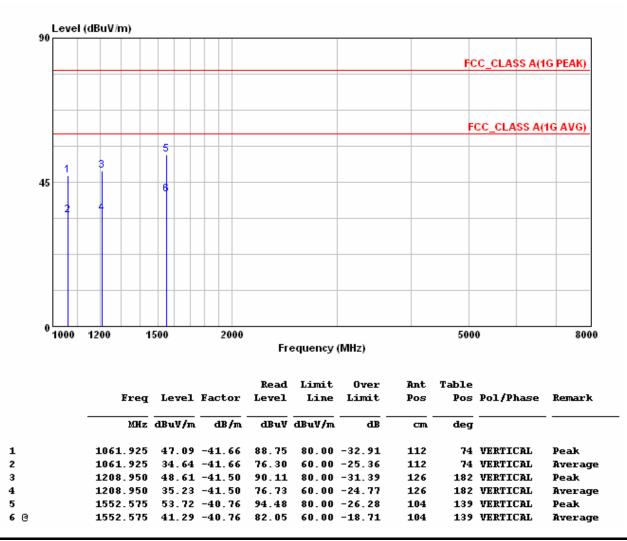
Test Mode : Normal

Test Voltage: 120V/60Hz to the power adapter

Tester: Meng Lin **Temperature**: 23°C

Humidity: 65%RH Frequency Range: 1GHz ~8GHz

IF Bandwidth: 1MHz Polarization: Vertical



Note:

- Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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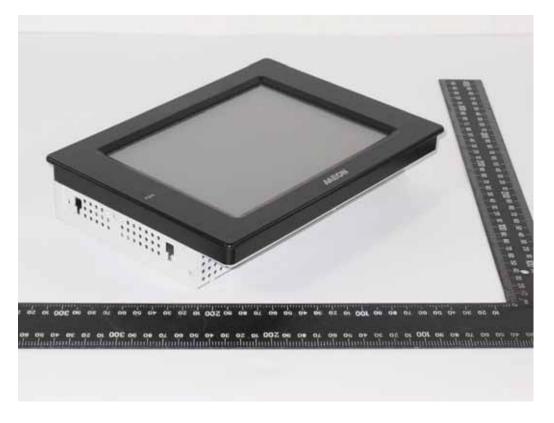
Attachment 1 Photographs of EUT

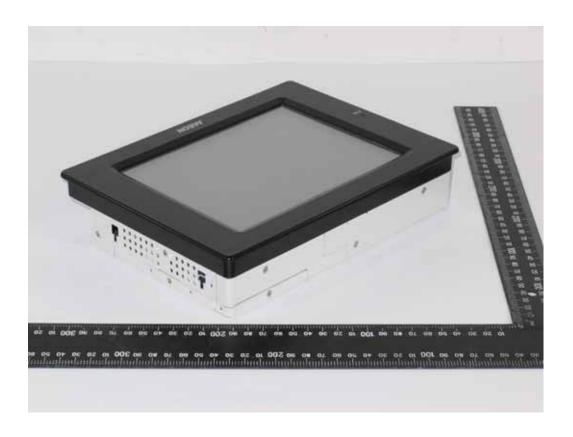
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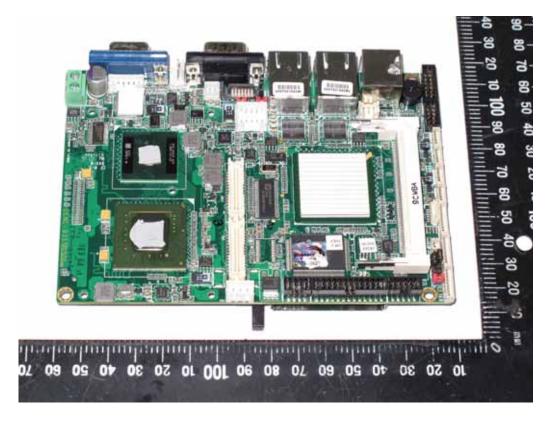






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FAX.: 886-2-25984546

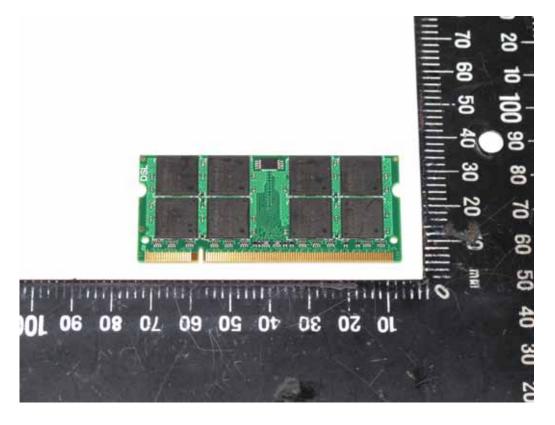


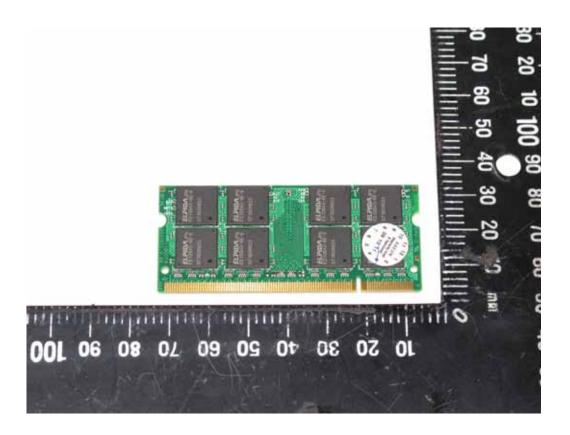


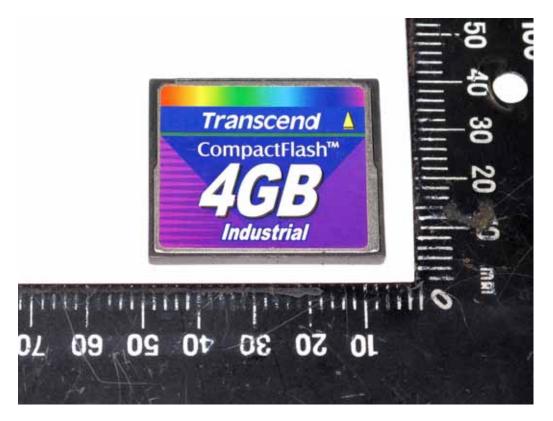




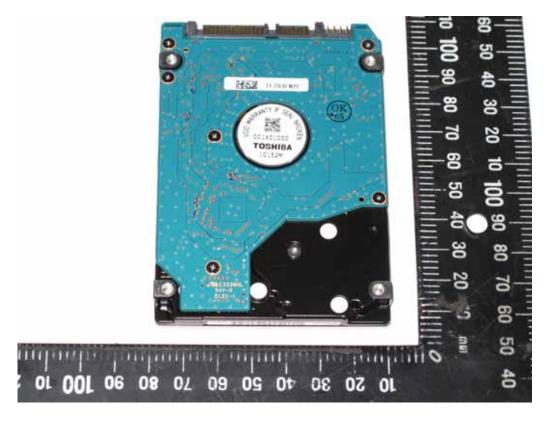


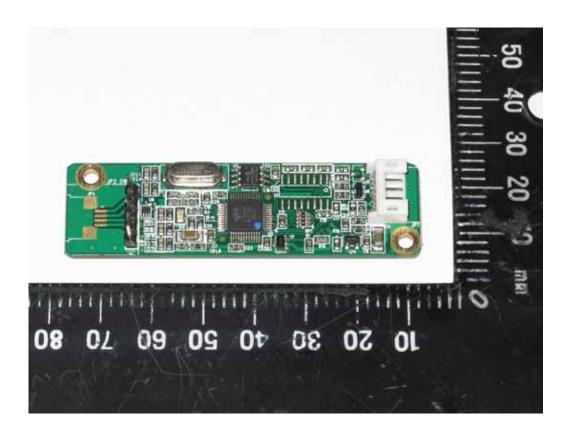


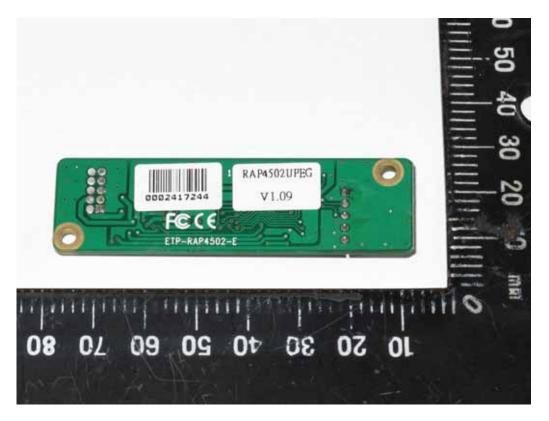


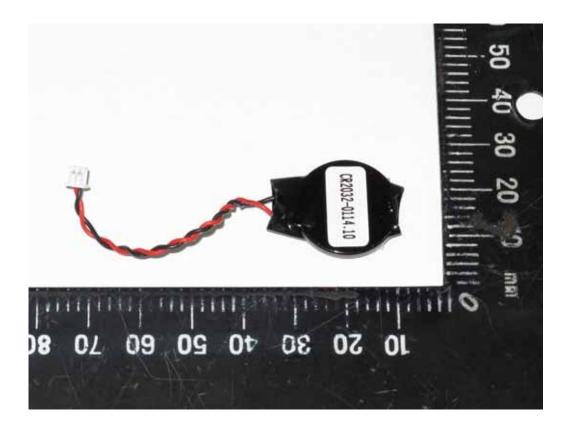
















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Attachment 2 Modifications of EUT

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Statement of the EUT Modifications

According to the rules of ANSI C63.4-2003 clause 10.1.13, the following equipment (EUT):

Report No.:F-U070-1009-255

Product	: Fanless Touch Panel					
Model No.	:	xxxxxAHP-1081xTy –xxxxx				
		(Where y is T or blank ; x purpose	is 0-9	, A-Z , -or blank) for marketing		
Manufacturer	:	AAEON Technology Inc.				
Address	:	5F,No.135,Lane 235,Pao (Chiao F	Rd. Hsin-Tien City,Taipei,		
		Taiwan,R.O.C.				
□ should be <u>witl</u>	<u>hout</u>	any modifications made				
□ should be <u>witl</u>	<u>h</u> so	me modifications made				
Subpart B). If an	y, th	• • • • • • • • • • • • • • • • • • • •	s includ	specifications (47CFR Part 15, ding the complete descriptions, port.		
		I Technology Inc. hereby I have all of the modification aced on the market.	ensu ons inc	re that the product specified orporated in the product when		
The following im	porte	er or manufacturer is respon	sible fo	or this statement:		
Company Name	:					
Company Addres	ss :					
Telephone	:		E-mai	il :		
Legal Signature	of th	e responsible personal:				

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The details of the modifications:

Item	Solution Component	Specifications	Manufacturer	Quantity	Reasons
1					
2					
3					
4					
5					
6					
7					
8					
9					
10					
11					
12					
13					
14					
15					

If needed, some modification items are shown in the photographs in the following.